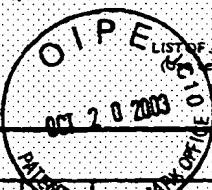
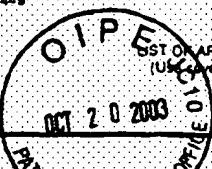


Form PTO-144		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M222-1363		SERIAL NO. 09/512,966	
 LIST OF ART CITED BY APPLICANT <small>(May cover several sheets if necessary)</small>					APPLICANT David Hembree			
					FILING DATE February 24, 2000		GROUP 2859	
U.S. PATENT DOCUMENTS								
Examiner Initial	Patent & Trademark Office Number	Date	Name		Class	Subclass	Filing Date if Appropriate	
VN	AA 5,612,574	3/18/97	Summerville et al.					
VN	AB 5,719,333	2/17/98	Hosoi et al.					
VN	AC 5,831,333	11/3/98	Malladi et al.					
VN	AD 5,919,548	7/6/99	Baron et al.					
VN	AE 5,551,283	9/3/96	Manaka et al.					
VN	AF 5,492,011	2/20/98	Amano et al.					
	AG							
	AH							
	AJ							
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country		Class	Subclass	Translation	
AK							Yes	No
AL								
AM								
AO								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
VN	AP	"NTC and PTC Thermistors": http://www.thermodisc.com/mptc.htm ; 1/7/98; 2 pages.						
VN	AR	"DI-5835 Linearized 4-Wire RTD Input": http://www.datasys.com/di5835.htm ; 1/7/98; 2 pages.						
VN	AS	"RTD": http://www.matsensors.com/rtds.htm ; 1/7/98; 3 pages.						
VN	AT	"Low Cost Thermal-Ribbon (TM) uses thin film RTD": http://www.mincos.com/s17824nr.htm ; 1/7/98; 1 page						
VN	AU	"Silicon Processing for the VLSI Era": Volume 1 - Process Technology, Second Edition, S. Wolf et al., 2000; pp. 22-25 and pp. 841-845.						
EXAMINER <u>vnh/Nguyen</u>		DATE CONSIDERED 01/22/04						
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 600. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M1221363	SERIAL NO. 09/512,968
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.	
				FILING DATE February 24, 2000	PRIORITY GROUP 2829 12050
U. S. PATENT DOCUMENTS					
Examiner Initials	Patent & Trademark Office Number	Date	Name	Class	Subclass
VN	AA 3,710,251	1/9/1973	Hagge et al.		
	AB				
	AC				
	AD				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)					
	AE				
	AF				
	AG				
	AH				
	AJ				
	AJ				
	AK				
	AL				
<u>EXAMINER</u>		<u>DATE CONSIDERED</u>			
<u>Mark Nguyen</u>				01/22/04	
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>					

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO MI221363	SERIAL NO 05/512 568
 <small>GST. OR ART CITED BY APPLICANT (Use several sheets if necessary)</small> <small>JAN 20 2003</small>				APPLICANT Micron Technology, Inc.	
				FILING DATE February 24, 2000	PRIORITY GROUP 2853
U.S. PATENT DOCUMENTS					
Examiner Initial	Patent & Trademark Office Application Number	Date	Name	Class	Subclass
VN	AA 4,355,463	10/26/1982	Burns		
	AB				
	AC				
	AD				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)					
AE					
AF					
AG					
AH					
AI					
AJ					
AK					
AL					
EXAMINER <i>Mark Nguyen</i>		DATE CONSIDERED <i>01/22/04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>					

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1363	SERIAL NO. 09/512 360	
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Micron Technology, Inc.		
					FILING DATE February 24, 2000	PRIORITY GROUP 2658	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
/N	AA	4,912,600	3/1990	Jaeger et al.	361	706	
/N	AB	5,436,494	7/1995	Mosidu	257	467	
/V	AC	5,969,639	10/1999	Laut et al.	340	875-17	
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AM						
	AJ						
	AK						
	AL						
EXAMINER <i>Mark Nguyen</i>				DATE CONSIDERED 01/22/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Indicate copy of this form with next communication to applicant.							